2123

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants:	Masahiro Ishida, et al.		
Serial No.:	09/699,077	Examiner:	Ayal Sharon
Filing Date:	October 27, 2000	Art Unit:	2123
Title:	Method and Apparatus for Fault Simulation of Semiconductor Integrated Circuit		

April 19, 2004

Commissioner of Patents
P.O. Box 1450
Alexandra, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

Pursuant to the duty of disclosure set forth in 37 CFR § 1.56, Applicants respectfully submit the following information disclosure statement.

The undersigned certifies that each of the following references was contained in a communication in connection with a counterpart foreign application not more than three months prior to the filing of this statement.

The disclosed reference is:

EPO 0 878 761, European Patent Office, published November 18, 1998.

Applicants respectfully request that the Examiner initial the cited references shown on the enclosed form PTO-1449 and that the references be made of record in the present application.

Respectfully submitted,

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Certificate of Mailing Under 37 CFR 1.8

I certify that this Information Disclosure Statement and all enclosed materials are being deposited with the United States Postal Service on April 19, 2004 with sufficient postage as first class mail in an envelope addressed to Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450..

David N. Lathrop

Enc. US PTO Form 1449
Cited reference (1)
Return receipt postcard

Form PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

INFORMATION DISCLOSURE STATEMENT

DOCKET	S.N.
KPO089	09/699,077
APPLICANT	
Masahiro Ishida, et al.	
FILING DATE	GROUP
October 27, 2000	2123

U.S. PATENT DOCUMENTS

*Exam. Initial		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB-CLASS	FILING DATE

FOREIGN PATENT DOCUMENTS

*Exam. Initial		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION YES	TRANSLATION NO
	EP	0 8 7 8 7 6 1	11-18-98	European Patent Office				

OTHER DOCUMENTS (*Including Author, Title, Date, Pertinent Pages, etc.*)

EXAMINER	DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP; draw line through citation if not in conformance and not considered. Include copy of this form with next communication with applicant.